

FORM PTO-1449	ATTY. DKT NO. 01-103-CON2	SER. NO. 10/699,954
	APPLICANT MAMITSU et al.	
	FILING DATE November 4, 2003	GROUP 1765

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS

TRANSLATION

	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
<i>AS</i>	JP-A-10-125700	05/15/98	JAPAN				Engl. Abstract	
<i>AS</i>	JP-A-61-147539	07/05/86	JAPAN				Engl. Abstract	

* Full English text of the JP Document will be available in machine-translated form from JP (Japanese Patent Office) English language web site at <http://www1.ipdl.jpo.go.jp/PA1/cgi-bin/PA1INDEX>.

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	<i>[Signature]</i>	DATE CONSIDERED <i>12/11/04</i>

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>[Signature]</i>	4,620,215	Oct., 1986	Lee, James C.K.		
<i>[Signature]</i>	6,472,305	Oct., 2002	Ozaki et al.		

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	TRANSLATION	
								YES	NO (Abstract)

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		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO (Abstract)
<i>PA</i>		JP-A-H07-66143	3/10/95	JAPAN					X
<i>PA</i>		JP-A-H09-237868	9/9/97	JAPAN					X
<i>PA</i>		JP-A-H09-45773	2/14/97	JAPAN					X
<i>PA</i>		JP-A-H11-204803	7/30/99	JAPAN					X

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>DA</i>	5,990,550	Nov. 23, 1999	Umezawa		
<i>DB</i>	5,608,610	Mar. 4, 1997	Brzezinski		
<i>DB</i>	5,396,403	Mar. 7, 1995	Patel		
<i>DB</i>	5,293,301	Mar. 8, 1994	Tanaka et al.		
<i>DB</i>	5,641,997	June 24, 1997	Ohta et al.		
<i>DB</i>	5,789,820	Aug. 4, 1998	Yamashita		

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								TRANSLATION	
	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS		YES	NO
<i>DB</i>	60-235430	11/85	JAPAN						
<i>DB</i>	07-240432	9/95	JAPAN						
<i>DB</i>	8-45874	2/96	JAPAN						
<i>DB</i>	60-95947	05/85	JAPAN						
<i>DB</i>	61-265849	11/86	JAPAN						
<i>DB</i>	62-141751	06/87	JAPAN						
<i>DB</i>	63-096946	04/88	JAPAN						
<i>DB</i>	62-92349	4/87	JAPAN						
<i>DB</i>	62-287649	12/87	JAPAN						
<i>DB</i>	59-38734	09/84	JAPAN						
<i>DB</i>	01-228138	09/89	JAPAN						
<i>DB</i>	54-40569	03/79	JAPAN						
<i>DB</i>	61-251043	11/86	JAPAN						
<i>DB</i>	54-95183	07/79	JAPAN						

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>DB</i>	2002/0158333	Oct. 31, 2002	Teshima		
<i>DB</i>	S/N 10/201556	July 24, 2002	Hirano et al.		
<i>DB</i>	5726466	March 10, 1998	Nishitani		
<i>DB</i>	4,470,063	Sep. 4, 1984	Arakawa et al.		
<i>DB</i>	5,708,299	Jan. 13, 1998	Teramae et al		

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TRANSLATION

	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
<i>DB</i>	59-031042	02/84	JAPAN					
<i>DB</i>	07-038013	02/95	JAPAN					
<i>DB</i>	07-273276	10/95	JAPAN					
<i>DB</i>	08-191145	07/96	JAPAN					
<i>DB</i>	2000-91485	03/00	JAPAN					
<i>DB</i>	W098/12748	3/26/98	PCT					
<i>DB</i>	JP-A-5-283562 *	10/29/93	JAPAN				X	
<i>DB</i>	JP-A-6-349987 *	12/22/94	JAPAN				X	
<i>DB</i>	JP-A-7-45765 *	2/14/95	JAPAN				X	
<i>DB</i>	JP-A-11-186469 *	7/9/99	JAPAN				X	
<i>DB</i>	JP-A-2000-31351 *	1/28/00	JAPAN				X	
<i>DB</i>	JP-A-2001-118961 *	4/27/01	JAPAN				X	

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<i>DB</i>	5,708,299	Jan. 13, 1998	Teramae et al		
<i>DB</i>	6,072,240	June 6, 2000	Kimura et al		
<i>DB</i>	5,248,853	Sep. 28, 1993	Ishikawa et al		
<i>DB</i>	5,801,445	Sep. 1, 1998	Ishihara et al		
<i>DB</i>	5,229,646	Jul. 20, 1993	Tsumura		
<i>DB</i>	4,558,345	Dec. 10, 1985	Dwyer et al		
<i>DB</i>	4,546,374	Oct. 8, 1985	Olsen et al		
<i>DB</i>	4,984,061	Jan. 8, 1991	Matsumoto		
<i>DB</i>	5,481,137	Jan 2, 1996	Harada et al.		
<i>DB</i>	4,827,082	May 2, 1989	Horiuchi et al		
<i>DB</i>	4,538,170	Aug. 27, 1985	Yerman		

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	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	TRANSLATION	
							YES	NO
<i>DB</i>	EP0660396	12/24/93	Europe					
<i>DB</i>	EP0450980	4/05/91	Europe					
<i>DB</i>	6-291223	10/94	JAPAN					
<i>DB</i>	3-20067	01/91	JAPAN					
<i>DB</i>	2146174	11/85	GB					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

<i>DB</i>	Takamura, "Electronic Technology", pp. 56-59 (1999-5).
<i>DB</i>	Johnson et al., "Silicon Precipitate Nodule-Induced Failures of MOSFETS", ISTFA '91 (Nov. 11-15, 1991), pp. 161-165.
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<i>DB</i>	12/11/04

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>RP</i>	4,646,129	Feb. 24, 1987	Yerman et al		
<i>RP</i>	4,141,030	Feb. 20, 1979	Eisele et al		
<i>RP</i>	6,448,645	Sep. 10, 2002	Kimura		
<i>RP</i>	6,538,308	Mar. 25, 2003	Nakase		
<i>RP</i>	6,380,622	Apr. 30, 2002	Hirai		
<i>RP</i>	09/675,209	Filed Sept. 29, 2000	Suzuki		
<i>RP</i>	5,221,851	Jun. 22, 1993	Gobrecht et al.		

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								TRANSLATION	
	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS		YES	NO
<i>RP</i>	4-249353	9/92	JAPAN						
<i>RP</i>	11-260979	09/99	JAPAN						
<i>RP</i>	4-27145	01/92	JAPAN						
<i>RP</i>	9-148492	06/97	JAPAN						
<i>RP</i>	4-12555	01/92	JAPAN						
<i>RP</i>	4-103150	04/92	JAPAN						
<i>RP</i>	60-137042	07/85	JAPAN						
<i>RP</i>	5-109919	04/93	JAPAN						
<i>RP</i>	61-166051	07/86	JAPAN						
<i>RP</i>	2-117157	05/90	JAPAN						
<i>RP</i>	63-102326	05/88	JAPAN						

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